

# High-Current Clip Flat Pin

## HKF-617 03208 080 A 10002

Item HKF-617-0009



GO TO PRODUCT

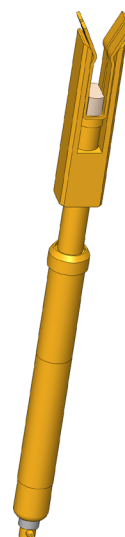
**ingun**<sup>®</sup>

Partner for Future Technology

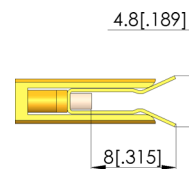
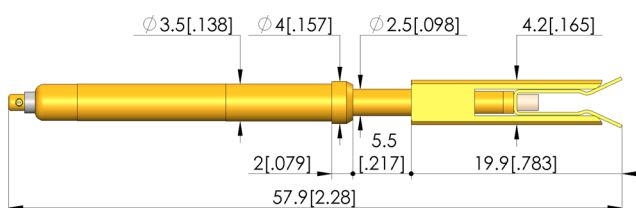
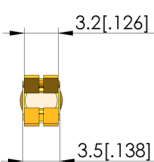
- Scratch-free contacting of flat contacts with compact design
- During the contacting process the contact lamellae are pressed against the flat connector blades without scratching.
- Current carrying capacity up to max. 40 A, depending on version

**INGUN SELECTION**

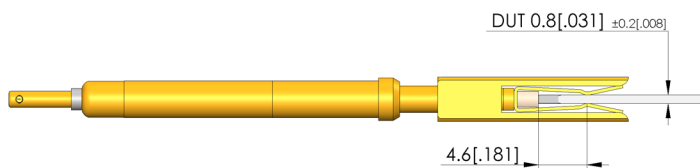
PATENT PENDING  
UTILITY MODEL



1:1



Example of contact at working stroke



### General data

Product group:	High-current clamps (flat/round)
Sub-product group:	High-current clamps (flat/round)
Series:	HKF-617
Grid:	6.5 mm [255 mil]
Contacting from:	Flat contact
Magnetic:	Yes
Installation type:	Bayonet
Quick-exchange system:	Yes
Adjustable installation height:	No
Non-rotating:	Yes
Compatible receptacle(s):	KS-617
Min. temperature:	-100 °C [-148 °F]
Max. temperature:	150 °C [302 °F]
RoHS-compliant:	Yes

### Tip style data

Tip style:	00-1 open, slotted
Tip diameter:	4.8 mm [.188 in]
Tip style surface:	A gold
Tip style material:	6 bronze

### Electrical data

Current load capacity / rated current:	20 A
--	------

HIGH-CURRENT TEST PROBES

# High-Current Clip Flat Pin HKF-617 03208 080 A 10002

Item HKF-617-0009



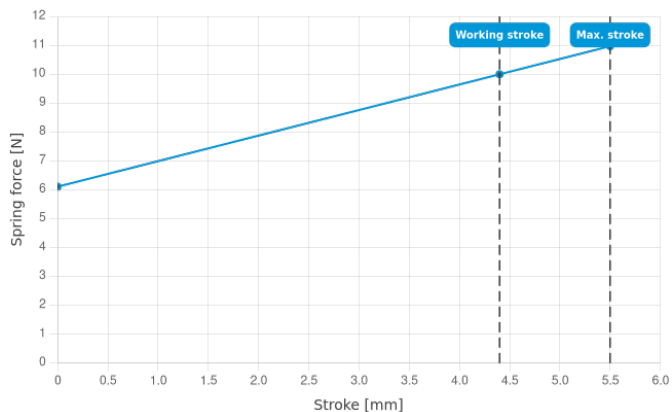
GO TO PRODUCT

**ingun**<sup>®</sup>

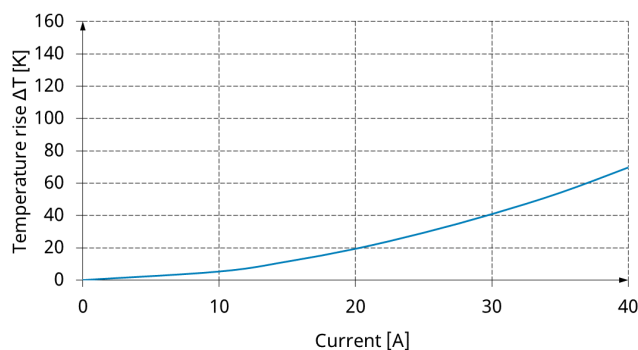
Partner for Future Technology

## Mechanical data

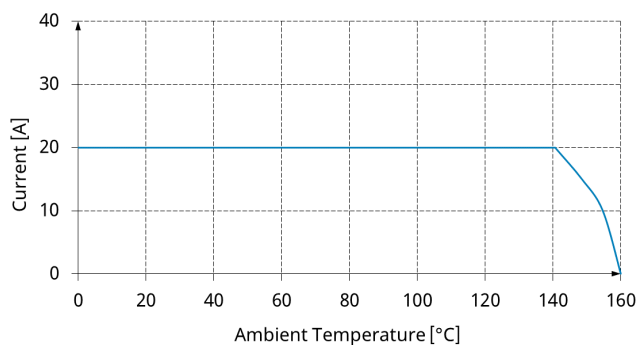
Total length:	57.9 mm [2.27 in]
Barrel diameter:	3.5 mm [.137 in]
Maximum stroke:	5.5 mm [.216 in]
Spring pre-load:	6.11 N [21.9 ozf]
Collar height:	02
Spring force at working stroke:	10 N [35.9 ozf]
Recommended working stroke:	4.4 mm [.173 in]



## Current Rating



## Current Derating



## INGUN Prüfmittelbau GmbH

Max-Stromeyer-Straße 162  
78467, Constance, Germany  
Phone +49 7531 8105-0  
Customer hotline +49 7531 8105-888  
Fax +49 7531 8105-65  
info@ingun.com



Prices and delivery times on request.  
Technical changes reserved. 05/26\_GB

Learn more about  
High-current test probes

